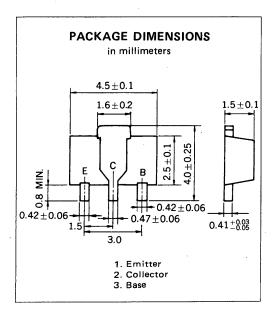


# SILICON TRANSISTOR 2SC3617

# NPN SILICON EPITAXIAL TRANSISTOR POWER MINI MOLD

### **DESCRIPTION**

2SC3617 is designed for audio frequency power amplifier and switching application, especially in Hybrid Integrated Circuits.



#### **FEATURES**

- World Standard Miniature Package
- High h<sub>FE</sub> h<sub>FE</sub> = 800 to 1600

# **ABSOLUTE MAXIMUM RATINGS**

Maximum Voltages and Currents (T <sub>a</sub> = 25	°C) ·		
Collector to Base Voltage	$V_{CBO}$	50	V
Collector to Emitter Voltage	$V_{CEO}$	50	V
Emitter to Base Voltage	$V_{EBO}$	15	V
Collector Current (DC)	lc .	300	mA
Collector Current (Pulse)*	lc	500	mΑ
Maximum Power Dissipation			
Total Power Dissipation			
at 25°C Ambient Temperature**	$P_T$	2.0	W
Maximum Temperatures			
Junction Temperature	Tj	150	°C
Storage Temperature Range	$T_{sta}$	-55 to +150	°C

<sup>\*</sup>PW  $\leq$  10 ms, Duty Cycle  $\leq$  50 %

# ELECTRICAL CHARACTERISTICS (Ta = 25 °C)

CHARACTERISTIC	SYMBOL	MIN.	TYP.	MAX.	UNIT	TEST CONDITIONS
Collector Cutoff Current	СВО			100	nA	V <sub>CB</sub> = 50 V, I <sub>E</sub> = 0
Emitter Cutoff Current	<sup>I</sup> EBO			100	nA	V <sub>EB</sub> = 10 V, I <sub>C</sub> = 0
DC Current Gain	hFE1 ***	800		3200		V <sub>CE</sub> = 5.0 V, I <sub>C</sub> = 100 mA
DC Current Gain	hFE2 ***	640				V <sub>CE</sub> = 5.0 V, I <sub>C</sub> = 300 mA
Collector Saturation Voltage	VCE (sat)***		0.12	0.13	V	I <sub>C</sub> = 100 mA, I <sub>B</sub> = 1.0 mA
Base Saturation Voltage	VBE(sat)***		0.7	1.2	· V	I <sub>C</sub> = 100 mA, I <sub>B</sub> = 1.0 mA
Gain Bandwidth Product	fT	150	220		MHz	V <sub>CE</sub> = 5.0 V, I <sub>E</sub> = -50 mA
Output Capacitance	C <sub>ob</sub>		8.0		pF	V <sub>CB</sub> = 10 V, I <sub>E</sub> = 0, f=1.0 MHz

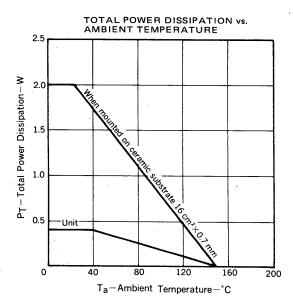
<sup>\*\*\*</sup>Pulsed: PW  $\leq$  350  $\mu$ s, Duty Cycle  $\leq$  2 %

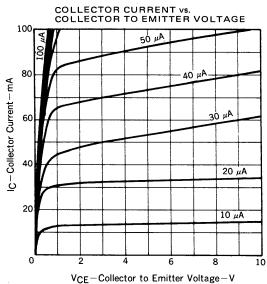
#### h<sub>FE</sub> Classification

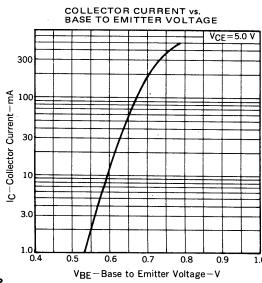
MARKING	ТМ	TL	TK .
hFE	800 to 1600	1200 to 2400	2000 to 3200

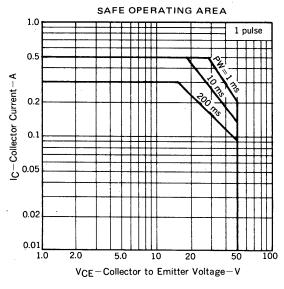
<sup>\*\*</sup>When mounted on ceramic substrate of 16 cm $^2$  x 0.7 mm

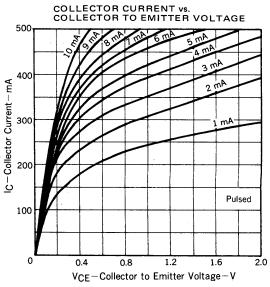
# TYPICAL CHARACTERISTICS (Ta= 25 °C)

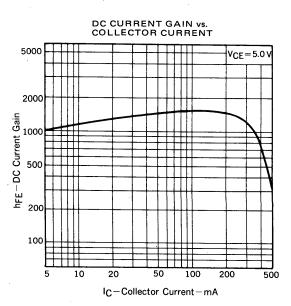


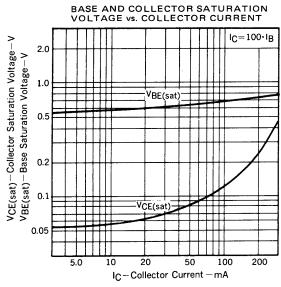


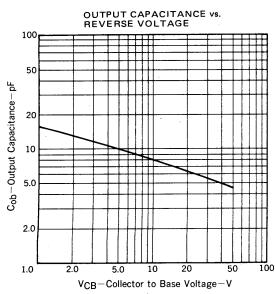


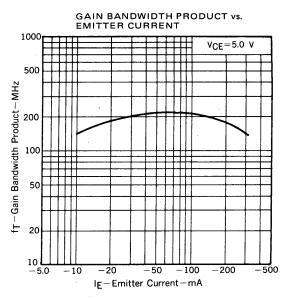


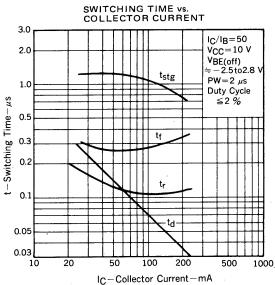












#### REFERENCE

Document Name	Document No.
NEC semiconductor device reliability/quality control system.	TEI-1202
Quality grade on NEC semiconductor devices.	IEI-1209
Semiconductor device mounting technology manual.	IEI-1207
Semiconductor device package manual.	IEI-1213
Guide to quality assurance for semiconductor devices.	MEI-1202
Semiconductor selection guide.	MF-1134

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Special: Automotive and Transportation equipment, Traffic control systems, Antidisaster systems, Anticrime systems, etc.

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